Substitute f	or form 14	49A/PTO	<del>-</del>	T	Com	plete if Known		
				Ar	pplication Number	09/848,519		
INFORMATION								
DISCLOSURE				Fil	ing Date	05/04/01		
STATEMENT BY APPLICANT				Fi	rst Named Inventor	David G. Beshore		
3	(C) 57				oup Art Unit	To be assigned		
יין די דועט	(Use as many sneets as necessary)				aminer Name	To be assigned		
Sheet	1	of	2	At	torney Docket Number	38190/233565		
16				LC	DATENIT DOCUMENTO			
Ť	1	U.S. Paten	t Document	<i>J.</i> 3.	PATENT DOCUMENTS	Date of	Pages, Columns, Lines,	
Examiner Initials*	Cite No. <sup>1</sup>	Number	Kind Co (if kno		Name of Patentee or Applicant Of Cited Document	Publication of Cited Document MM-DD-YYYY	Where Relevant Passages of Relevant Figures Appear	
(X)	1	5,737,494			Guinta et al.	04-07-1998		
VS	2	5,893,098			Peters et al.	04-06-1999		
W.	3	5,978,648			George et al.	11-02-1999		
(X)	4	5,987,149			Poor	11-16-1999		
L/V	5	6,092,060			Guinta et al.	07-18-2000		
OKS	6	6,151,581		•	Kraftson et al.	11-21-2000		
<b>W</b>	7	6,157,915			Bhaskaran et al.	12-05-2000		
(1)	8	6,161,101		•	Guinta et al.	12-12-2000		
U								
					•			
							,	
					PATENT DOCUME	NTS		
Examiner Initials	Cite No.	Foreign Pate Office <sup>3</sup> Number	nt Documen Kind C (if know	Code	Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	
						-		
				A				

\*Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Date

Considered

6-21-05

Examiner

Signature

<sup>&</sup>lt;sup>1</sup> Unique citation designation number.

<sup>&</sup>lt;sup>2</sup> See attached Kinds of U.S. Patent Documents.

<sup>&</sup>lt;sup>3</sup> Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3).

For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document.

<sup>&</sup>lt;sup>5</sup> Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible.

<sup>&</sup>lt;sup>6</sup> Applicant is to place an "X" here if English language Translation is attached.

	Substitute for form 1449A/PTO				Complete if Known		
					Application Number	09/848,519	
		INFO	RMATIO	N			
OIP		DISC	CLOSURE	;	Filing Date	05/04/01	
	SXA	TEMEN	ΓBY APP	LICANT	First Named Inventor	David G. Beshore	
	3				Group Art Unit	To be assigned	
. JUN 0 4 2	7 55	(Use as many sheets as necessary)			Examiner Name	To be assigned	
TEN	She	2	of	2	Attorney Docket Number	38190/233565	
PADEMAN	* GE						

## NON PATENT LITERATURE DOCUMENTS

Examiner	Cite	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item	
Examiner Initials	No.	(book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	1
YS.	9	MARK C. PAULK, BILL CURTIS, MARY BETH CHRISSIS & CHARLES V. WEBER, Capability Maturity Model, Version 1.1, 10 IEEE SOFTWARE 18-27 (July 1993), reprinted as, The Capability Maturity Model for Software, available at <a href="http://www.sei.cmu.edu/cmm/papers/cmm.pdf">http://www.sei.cmu.edu/cmm/papers/cmm.pdf</a> (visited 2001), 26 total pages	
(XS	10	MARK C. PAULK, Effective CMM-Based Process Improvement, PROCEEDINGS OF THE 6TH INT'L CONF. ON SOFTWARE QUALITY, OTTAWA, CAN. 226-237 (Oct. 28-31, 1996), available at <a href="http://www.sci.cmu.edu/cmm/papers/effective-spi.pdf">http://www.sci.cmu.edu/cmm/papers/effective-spi.pdf</a> (visited 2001), 12 total pages.	
O CX	11	SOFTWARE ENGINEERING INSTITUTE (SEI), A SYSTEMS ENGINEERING CAPABILITY MATURITY MODEL, VERSION 1.1 (1995), available at <a href="http://www.sei.cmu.edu/pub/documents/95.reports/pdf/mm003.95.pdf">http://www.sei.cmu.edu/pub/documents/95.reports/pdf/mm003.95.pdf</a> , 70 selected pages.	
IX IX	12	ELECTRONIC INDUSTRIES ALLIANCE (EIA), SYSTEMS ENGINEERING CAPABILITY MODEL APPRAISAL METHOD, available at (last modified Feb. 26, 2001) <a href="http://www.geia.org/sstc/G47/731dwnld.htm">http://www.geia.org/sstc/G47/731dwnld.htm</a> , 161 total pages.	
β? I	13	DONNA K. DUNAWAY & STEVE MASTERS, CMM <sup>SM</sup> -BASED APPRAISAL FOR INTERNAL PROCESS IMPROVEMENT (CBA IPI): METHOD DESCRIPTION (1996), available at <a href="http://www.sei.cmu.edu/pub/documents/96.reports/pdf/tr007.96.pdf">http://www.sei.cmu.edu/pub/documents/96.reports/pdf/tr007.96.pdf</a> >, 57 total pages.	
V			

Examiner Signature	D. A. 1	Date Considered	6-21-05
O.B.idiao		Collsidered	<b>V</b>

\*Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.